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L4	160	((count near2 value\$1) same payload)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	SAME	ON	2005/02/16 14:43
L5	26	"5801781" and count\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	SAME	ON	2005/02/16 14:44

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